

## CHICAGO SECTION 1312

By William Wright, Co-Chair



Continuing with the success of the revitalized section meetings, the NCSLI Chicago Section 1312 held yet another successful meeting on November 8, 2011, which was packed full of information for all in attendance.

The meeting was held at the Greenbelt Cultural Center in North Chicago and was hosted by Abbott Laboratories. Despite the heavy rainfall, 55 people, representing a very wide range of industries, participated in this event.

Jim Salsbury (Mitutoyo America Corp.) began the meeting with introductions and logistics. This was followed by a quick yet informative welcome from the meeting's host, Abbott Laboratories. Rodica Caratas presented to the audience a bit of Abbott Laboratories' history, current agenda and future plans.

Elizabeth Gentry (NIST) kicked off the technical talks with her presentation titled "Measurement Uncertainty to Support Legal Metrology." At the end of her presentation, audience members were able to identify resources and availability that are required for State Weights and Measures Laboratory Recognition; list key requirements for demonstrating measurement traceability for weights and measures (legal) metrology; and describe the process by which traceability hierarchies and uncertainty analyses and reporting are documented and assessed.

Elizabeth continued with another presentation on "Metrology for the Next Generation." This presentation highlighted the importance of metrology education for the youth and potential hires of the nation. It also touched on having current metrology experts reach out to those in need of metrology education to increase enthusiasm and awareness. Elizabeth gave many sources and contacts for those who desire to reach out for educational purposes.

Patrick Butler (Fluke Corp.) presented "Implementing *ISO/IEC 17025* Measurement Uncertainty Requirements in Software" with great results. He illustrated details on the automation of recording and reporting data (specifically uncertainties) while staying in compliance with *ISO/IEC 17025*.

Paul Reese (NASA) concluded the technical discussions with a phenomenal presentation titled "Risk Mitigation and *ANSI/NC-SLI Z540.3* Compliance." Everyone present thoroughly enjoyed his presentation on *ANSI/NC-SLI Z540.3* and its unique take on risk management. Several questions soon followed which led to many in the audience wanting more information in the next meeting.

Towards the end of the day, Abbott Laboratories provided an in-depth visit of their metrology department, including a behind-the-scenes tour of their calibration labs. All who attended were very thankful to have the rare opportunity to get such an exclusive visit. Tour guides included Robert (Bob) Mielke, Joe Petersen, John Madrid, Anthony McMillian and Rodica Caratas.

Thanks go out to Northrop Grumman, NCSLI and Mitutoyo for their assistance in donating great hand-outs and door prizes for this section meeting! A special thank you to the host company Abbott Laboratories, for providing lunch, other refreshments, the outstanding lab tour, and a great location. The Chicago section has tentatively scheduled its next meeting for May 23, 2012 at Baxter Healthcare Corporation in Round Lake, Illinois.

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Chicago section meeting.